

2008 Automotive EMC Standards Workshop

Presentation & Discussion Topic	Type	INTERNATIONAL STANDARD	Time	Min	Discussion Lead
Welcome & Introductions (DAY 1)	Admin.		8:00	0:10	Williams
Welcome to U/M-Dearborn (U/M-D Provost)	Admin.		8:10	0:05	Shridhar
A Standards Map (International / National & Company Stds.)	Roadmap	ALL	8:15	0:30	Andersen
Test Lab Certification (AEMCLAP / AEMCLRP / A2LA)	Roadmap	ISO 17025	8:45	0:40	Banasky
Questions and Answers	Clarification		9:25	0:30	Andersen
AM Break (Special Info. Topic: Participation in Standards Activities)	Functional		9:55	0:20	Andersen
RI, ALSE	Test Method(s)	ISO 11452-2	10:15	1:00	Frazier
OEM Implementation			11:15	0:15	Frazier
AEMCLRP			11:30	0:05	Frazier
Expected Changes			11:35	0:05	Frazier
Questions and Answers	Clarification		11:40	0:20	Andersen
Lunch	Functional		12:00	1:00	
Personnel Certification (iNARTE)	Roadmap	ISO 17024	13:00	0:30	Lawrence
Questions and Answers	Clarification		13:30	0:10	Andersen
RI, Reverberation Chamber	Test Method(s)	IEC 61000-4-21	13:40	0:45	Banasky
OEM Implementation			14:25	0:05	Banasky
AEMCLRP			14:30	0:05	Banasky
Expected Changes			14:35	0:05	Banasky
Questions and Answers	Clarification		14:40	0:10	Andersen
PM Break (Special Info. Topic: Automotive iNARTE Question Pool)	Functional		14:50	0:20	Williams
RI, Transverse Electromagnetic Mode Cell (TEM CELL)	Test Method(s)	ISO 11452-3	15:10	0:30	Kado/Shune
OEM Implementation			15:40	0:00	Kado/Shune
AEMCLRP			15:40	0:00	Kado/Shune
Expected Changes			15:40	0:00	Kado/Shune
Questions and Answers	Clarification		15:40	0:10	Andersen
RI, Bulk Current Injection (BCI)	Test Method(s)	ISO 11452-4	15:50	0:30	Banasky
OEM Implementation			16:20	0:10	Banasky
AEMCLRP			16:30	0:10	Banasky
Expected Changes			16:40	0:05	Banasky
Questions and Answers	Clarification		16:45	0:10	Andersen
Closing Remarks & Thank You (Day 1)	Admin.		16:55	0:05	Williams
Close of Day 1	Admin.		17:00		
			Day 1	9:00	Hours

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Presentation & Discussion Topic	Type	INTERNATIONAL STANDARD	Time	Min	Discussion Lead
Welcome & Introductions (DAY 2)	Admin.		8:00	0:10	Williams
Conducted RF Emissions (CE)	Test Method(s)	CISPR 25-3rd Ed.	8:10	0:20	Kado/Shune
OEM Implementation			8:30	0:10	Kado/Shune
AEMCLRP			8:40	0:20	Kado/Shune
Expected Changes			9:00	0:10	Kado/Shune
Questions and Answers	Clarification		9:10	0:10	Andersen
AM Break	Functional		9:20	0:20	
Radiated Emissions (ALSE / RE)	Test Method(s)	CISPR 25-3rd Ed.	9:40	0:30	Frazier
OEM Implementation			10:10	0:20	Frazier
AEMCLRP			10:30	0:10	Frazier
Expected Changes			10:40	0:10	Frazier
Questions and Answers	Clarification		10:50	0:10	Andersen
Conducted Emissions-Transients (CET)	Test Method(s)	ISO 7637-2	11:00	0:30	Banasky
OEM Implementation			11:30	0:10	Banasky
AEMCLRP			11:40	0:05	Banasky
Expected Changes			11:45	0:05	Banasky
Questions and Answers	Clarification		11:50	0:10	Andersen
Lunch	Functional		12:00	1:00	
Conducted Immunity-Transients: (CIT / Direct)	Test Method(s)	ISO 7637-2	13:00	1:00	Frazier
Conducted Immunity-Transients: (CIT / Coupled)	Test Method(s)	ISO 7637-3	14:00	0:20	Frazier
OEM Implementation			14:20	0:10	Frazier
AEMCLRP			14:30	0:05	Frazier
Expected Changes			14:35	0:05	Frazier
Questions and Answers	Clarification		14:40	0:20	Andersen
PM Break (Raffle off 1 Free Admission to EMC2008 Symposium)	Functional		15:00	0:20	Williams
Electrostatic Discharge (ESD)	Test Method(s)	ISO 10605	15:20	0:30	Banasky
OEM Implementation			15:50	0:10	Banasky
AEMCLRP			16:00	0:10	Banasky
Expected Changes			16:10	0:05	Banasky
Questions and Answers	Clarification		16:15	0:10	Andersen
Closing Remarks & Thank You to ALL (Day 2)	Admin.		16:25	0:05	Williams
Close of Day 2	Admin.		16:30		

Day 2 8:30 Hours
Total hrs 17:30